

**P-Channel Enhancement Mode MOSFET**
**◆ DESCRIPTION**

The MT3413 is the P-Channel logic enhancement mode power field effect transistors are produced using high cell density, DMOS trench technology.

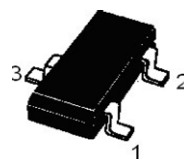
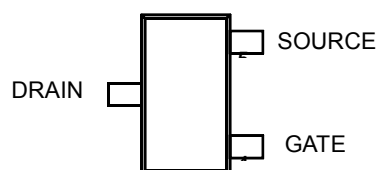
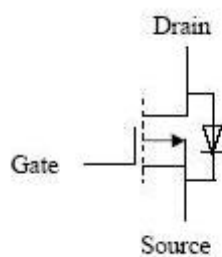
This high density process is especially tailored to minimize on-state resistance. These devices are particularly suited for low voltage application such as cellular phone and notebook computer power management and other batter powered circuits where high-side switching, and low in-line power loss are needed in a very small outline surface mount package

**◆ FEATURES**

- -20V/-3.4A,  $R_{DS(ON)} = 95 \text{ m}\Omega @ V_{GS} = -4.5\text{V}$
- -20V/-2.6A,  $R_{DS(ON)} = 120 \text{ m}\Omega @ V_{GS} = -2.5\text{V}$
- -20V/-1A,  $R_{DS(ON)} = 145 \text{ m}\Omega @ V_{GS} = -1.8\text{V}$
- Super high density cell design for extremely low  $R_{DS(ON)}$
- Exceptional on-resistance and maximum DC current capability

**◆ APPLICATIONS**

- POWER Management in Note
- Portable Equipment
- Battery Powered System
- DC/DC Converter
- Load Switch
- DSC

**◆ PIN CONFIGURATION**


**◆ ABSOLUTE MAXIMUM RATINGS**

 (T<sub>A</sub>=25°C Unless Otherwise Noted)

Parameter	Symbol	Maximum	Unit
Drain-Source Voltage	V <sub>DS</sub>	-20	V
Gate-Source Voltage	V <sub>GS</sub>	± 12	V
Continuous Drain Current	I <sub>D</sub>	T <sub>A</sub> = 25°C	-3.4
		T <sub>A</sub> = 70°C	-2.4
Pulsed Drain Current	I <sub>DM</sub>	-15	A
Continuous Source Current (Diode Conduction)	I <sub>S</sub>	-2	A
Power Dissipation	P <sub>D</sub>	T <sub>A</sub> = 25°C	1.4
		T <sub>A</sub> = 70°C	0.9
Operating junction temperature range	T <sub>J</sub>	150	°C
Storage temperature range	T <sub>STG</sub>	- 55 to 150	°C

**◆ THERMAL RESISTANCE RATINGS**

Parameter	Symbol	Maximum	Unit
Junction-to-Ambient	R <sub>θJA</sub>	100	°C/W

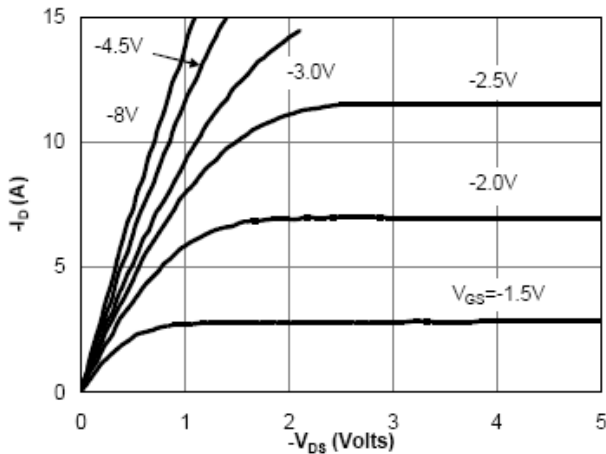
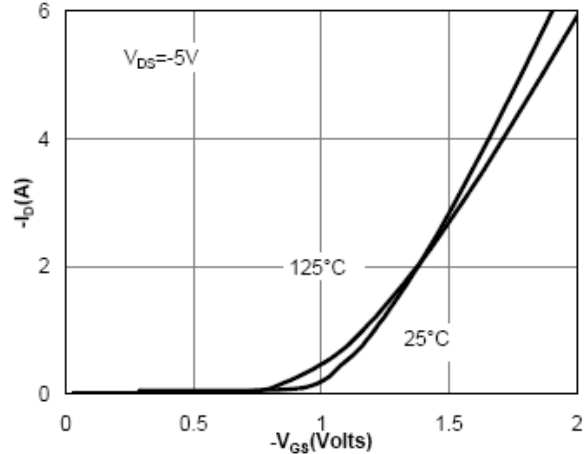
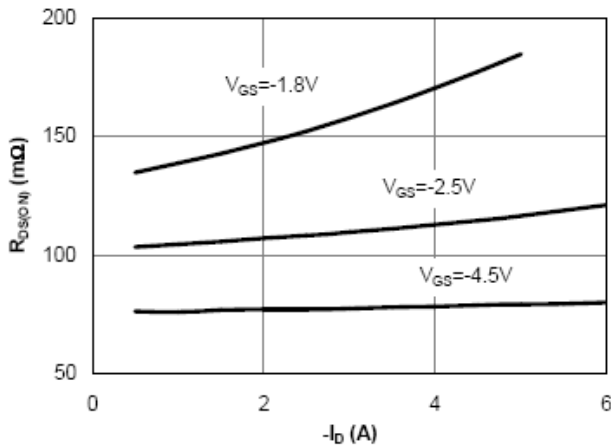
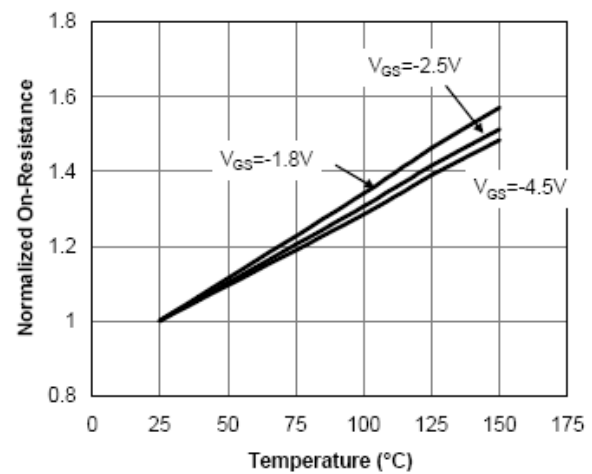
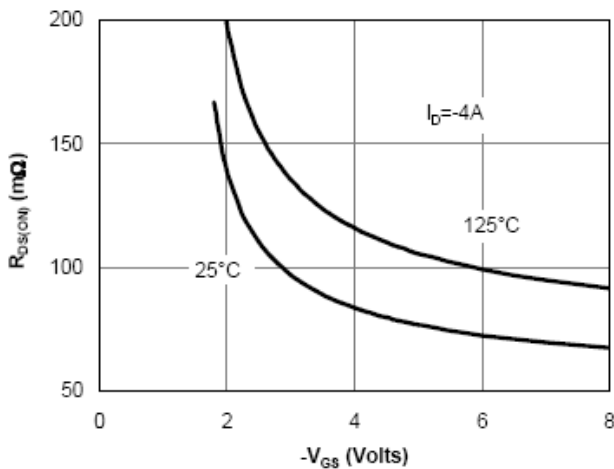
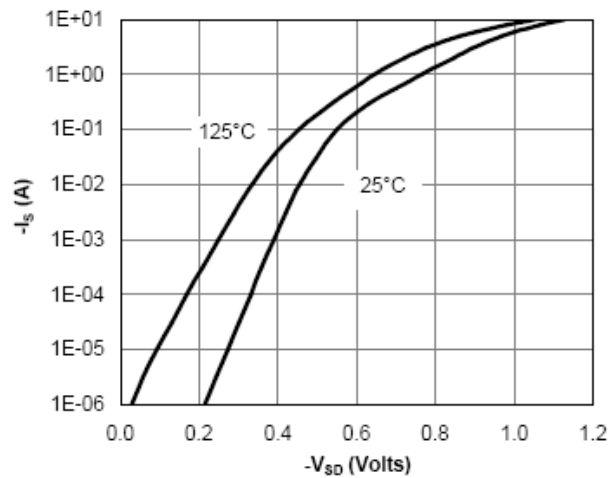
**◆ ORDERING INFORMATION**

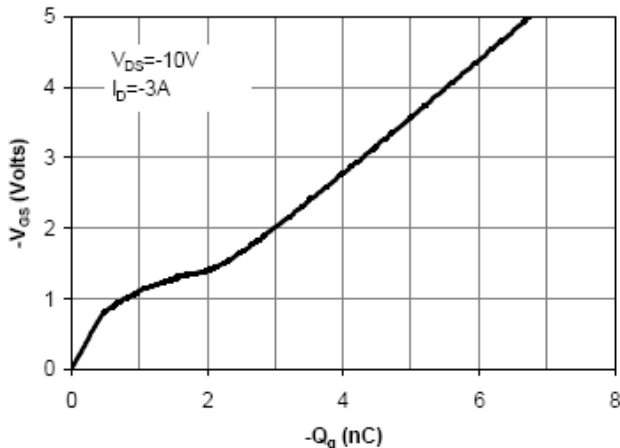
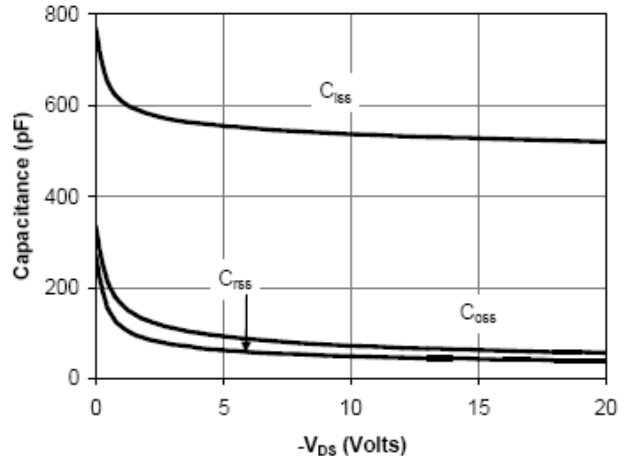
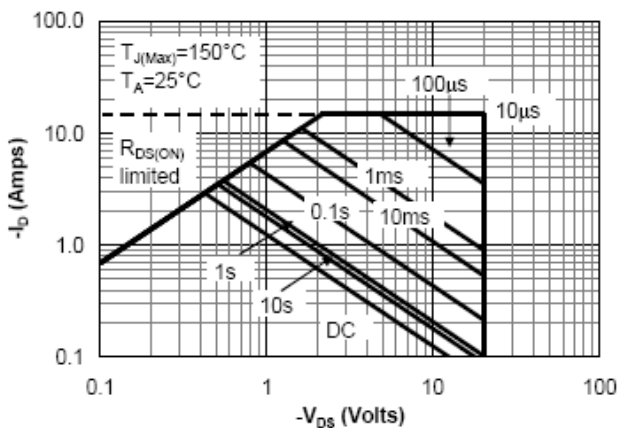
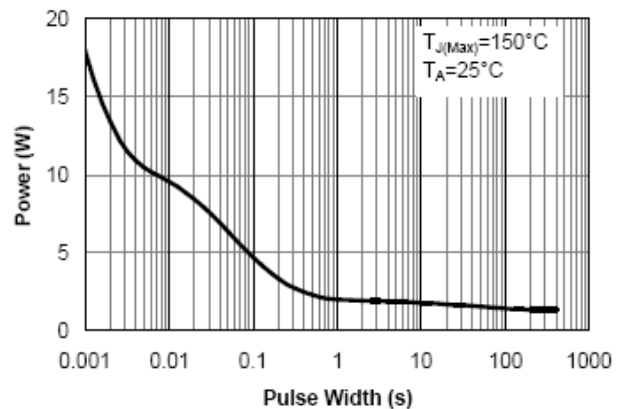
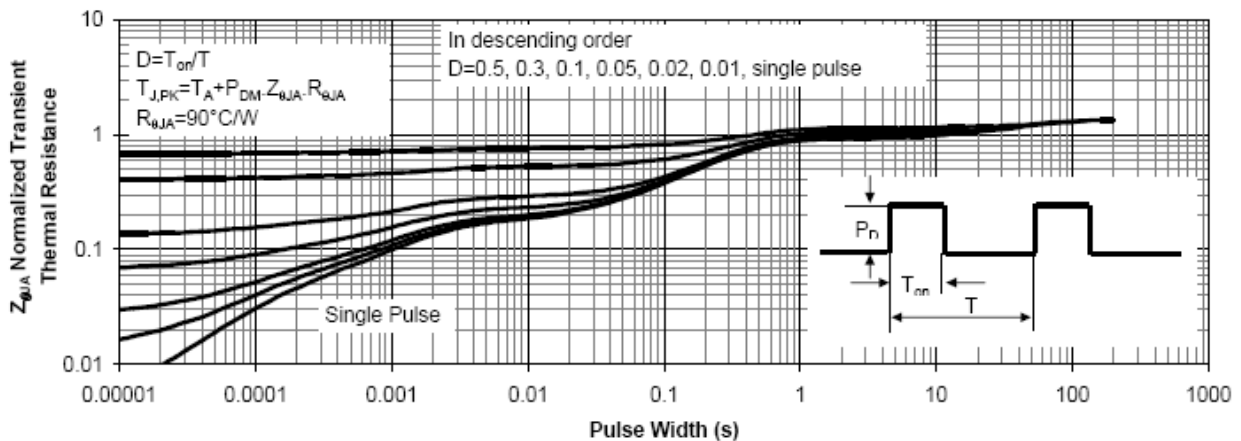
Device	Package	Shipping
MT3413	SOT-23	3000 PCS / Tape & Reel

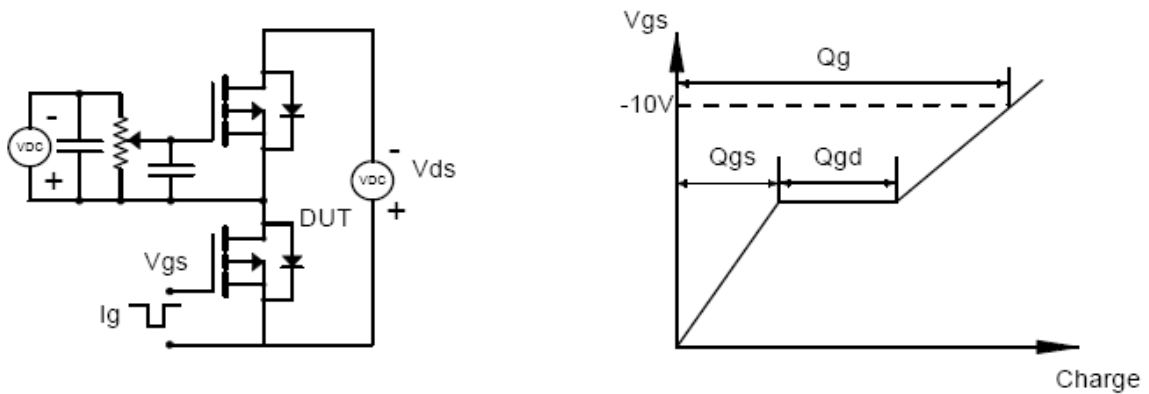
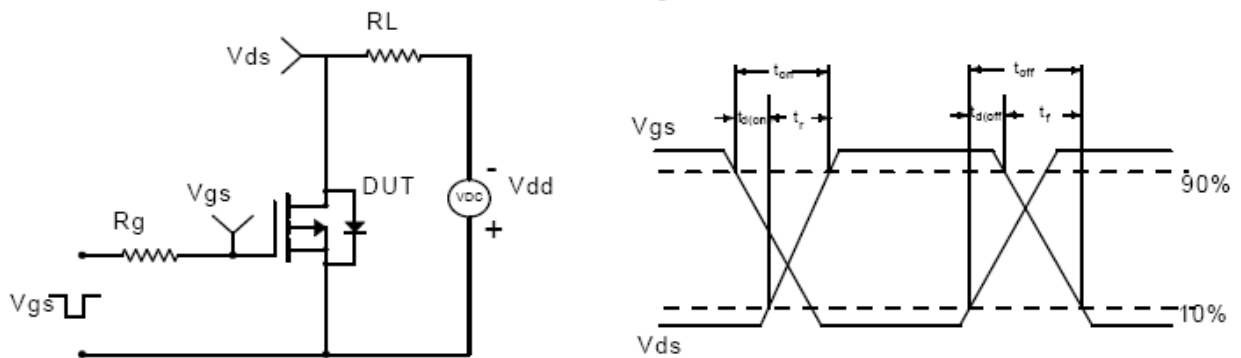
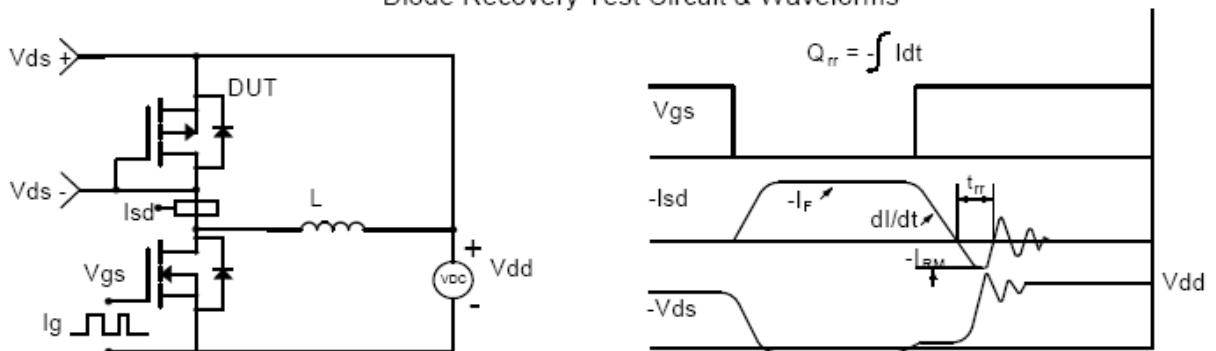
**◆ ELECTRICAL CHARACTERISTICS**

 (T<sub>A</sub>=25°C Unless Otherwise Noted)

Static Parameters						
Parameter	Symbol	Test Conditions	Min.	Typ.	Max.	Unit
Drain-Source Breakdown Voltage	V <sub>(BR)DSS</sub>	V <sub>GS</sub> = 0V, I <sub>D</sub> = 250μA	-20	-	-	V
Gate Threshold Voltage	V <sub>GS(th)</sub>	V <sub>GS</sub> = V <sub>DS</sub> , I <sub>D</sub> = 250μA	0.4	-	0.8	V
Gate Leakage Current	I <sub>GSS</sub>	V <sub>DS</sub> = 0V, V <sub>GS</sub> = ± 12 V	-	-	±100	nA
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	V <sub>DS</sub> = -20V, V <sub>GS</sub> = 0 V	-	-	1	μA
		V <sub>DS</sub> = -20V, V <sub>GS</sub> = 0V, T <sub>J</sub> = 55 °C	-	-	5	
Forward Trans conductance	g <sub>fs</sub>	V <sub>DS</sub> = -5V, I <sub>D</sub> = -3.4A	-	7	-	S
On-State Drain Current	I <sub>D(ON)</sub>	V <sub>DS</sub> ≤ -5V, V <sub>GS</sub> = -4.5V	-15	-	-	A
Drain-Source On Resistance	R <sub>DS(ON)</sub>	V <sub>GS</sub> = -4.5V, I <sub>D</sub> = -3.4A	-	80	95	mΩ
		V <sub>GS</sub> = -2.5V, I <sub>D</sub> = -2.6A	-	105	120	
		V <sub>GS</sub> = -1.8V, I <sub>D</sub> = -1.0A	-	130	145	
Diode Forward Voltage	V <sub>SD</sub>	I <sub>S</sub> = -1.0A, V <sub>GS</sub> = 0V	-	0.75	-1.0	V
Dynamic Parameters						
Parameter	Symbol	Test Conditions	Min.	Typ.	Max.	Unit
Input Cap.	C <sub>iss</sub>	V <sub>DS</sub> = -10V, V <sub>GS</sub> = 0V, F = 1MHz	-	540	-	pF
Output Cap.	C <sub>oss</sub>		-	72	-	
Reverse Transfer Cap.	C <sub>rss</sub>		-	49	-	
Total Gate Charge	Q <sub>g</sub>	V <sub>DS</sub> = -10V, V <sub>GS</sub> = -4.5V, I <sub>D</sub> = -1.0A	-	6.1	-	nC
Gate-Source Charge	Q <sub>gs</sub>		-	0.6	-	
Gate-Drain Charge	Q <sub>gd</sub>		-	1.6	-	
Turn-On Time	T <sub>D(ON)</sub>	V <sub>DS</sub> = -10V, R <sub>L</sub> = 3.3Ω, V <sub>GEN</sub> = -4.5V, R <sub>G</sub> = 3Ω	-	10	-	nS
	t <sub>r</sub>		-	12	-	
Turn-Off Time	T <sub>D(OFF)</sub>		-	44	-	
	t <sub>f</sub>		-	22	60	

**P-Channel Enhancement Mode MOSFET**
**◆ TYPICAL CHARACTERISTICS**

**Fig 1: On-Region Characteristics**

**Figure 2: Transfer Characteristics**

**Figure 3: On-Resistance vs. Drain Current and Gate Voltage**

**Figure 4: On-Resistance vs. Junction Temperature**

**Figure 5: On-Resistance vs. Gate-Source Voltage**

**Figure 6: Body-Diode Characteristics**

**◆ TYPICAL CHARACTERISTICS**

**Figure 7: Gate-Charge Characteristics**

**Figure 8: Capacitance Characteristics**

**Figure 9: Maximum Forward Biased Safe Operating Area (Note E)**

**Figure 10: Single Pulse Power Rating Junction-to-Ambient (Note E)**

**Figure 11: Normalized Maximum Transient Thermal Impedance**

**◆ TYPICAL CHARACTERISTICS**
**Gate Charge Test Circuit & Waveform**

**Resistive Switching Test Circuit & Waveforms**

**Diode Recovery Test Circuit & Waveforms**


**◆ PHYSICAL DIMENSIONS**
**3-Pin surface Mount SOT-23(S)**
